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MOSFET – Power, Single, N-Channel, SO-8FL 30 V, 191 A

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These are Pb-Free Devices

Applications

- Refer to Application Note AND8195/D
- CPU Power Delivery
- DC-DC Converters
- Low Side Switching

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain		T _A = 25°C	I _D	28	Α
Current R _{θJA} (Note 1)		T _A = 85°C		20.5	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	2.7	W
Continuous Drain	1	T _A = 25°C	ID	16	Α
Current R _{θJA} (Note 2)	Steady	T _A = 85°C		12	
Power Dissipation R _{θJA} (Note 2)	State	T _A = 25°C	P _D	1.1	W
Continuous Drain		T _C = 25°C	I _D	191	Α
Current R _{θJC} (Note 1)		T _C = 85°C		138	
Power Dissipation R _{θJC} (Note 1)		T _C = 25°C	P _D	113.6	W
Pulsed Drain Current	, ,	= 25°C, = 10 μs	I _{DM}	288	Α
Operating Junction and Storage Temperature			T _J , T _{STG}	-55 to +150	°C
Source Current (Body	I _S	104	Α		
Drain to Source dV/dt			dV/dt	6	V/ns
Single Pulse Drain-to-Source Avalanche Energy (T_J = 25°C, V_{DD} = 30 V, V_{GS} = 10 V, I_L = 35 A_{pk} , L = 1.0 mH, R_G = 25 Ω)			EAS	612.5	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			T _L	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

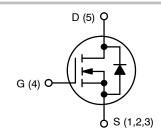
1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.



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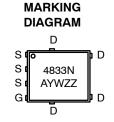
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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	2.0 mΩ @ 10 V	
30 V	3.0 m Ω @ 4.5 V	191 A



N-CHANNEL MOSFET





A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4833NT1G	SO-8FL (Pb-Free)	1500/Tape & Reel
NTMFS4833NT3G	SO-8FL (Pb-Free)	5000/Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

2.	Surface-mounted on FR4 board using the minimum recommended pad size. (Cu area = 50 mm² [1 oz])

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	1.1	
Junction-to-Ambient - Steady State (Note 3)	$R_{ hetaJA}$	45.6	°C/W
Junction-to-Ambient - t < 10s (Note 3)	$R_{ heta JA}$	17.1	-0/٧٧
Junction-to-Ambient - Steady State (Note 4)	$R_{ heta JA}$	117.4	

- 3. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.4. Surface-mounted on FR4 board using the minimum recommendation. ommended pad size. (Cu area = 50 mm² [1 oz])

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•						
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J				17		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25 °C			1	μΑ
		V _{DS} = 24 V	T _J = 125°C			10	
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS}	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)	•						
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = I_{DS}$	= 250 μΑ	1.5		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				7.12		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V to	I _D = 30 A		1.3	2.0	1
		11.5 V	I _D = 15 A		1.3		_
		V _{GS} = 4.5 V I _D = 30 A 2.3	2.3	3.0	mΩ		
			I _D = 15 A		2.3		1
Forward Transconductance	9 _{FS}	V _{DS} = 15 V, I _D = 15 A			30		S
CHARGES, CAPACITANCES & GATE RESIS	STANCE				•		•
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 12 V			5600		pF
Output Capacitance	C _{OSS}				1200		
Reverse Transfer Capacitance	C _{RSS}				650		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A			39	58	
Threshold Gate Charge	Q _{G(TH)}				6.0		
Gate-to-Source Charge	Q_{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 1$	5 V; I _D = 30 A		16		nC
Gate-to-Drain Charge	Q_{GD}	1			17		1
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 11.5 V, V _{DS} = 15 V; I _D = 30 A			88		nC
SWITCHING CHARACTERISTICS (Note 6)							
Turn-On Delay Time	t _{d(ON)}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}, I_{D} = 15 \text{ A},$ $R_{G} = 3.0 \Omega$			25		
Rise Time	t _r				34		ns
Turn-Off Delay Time	t _{d(OFF)}				35		
Fall Time	t _f				17		1
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 11.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			14		
Rise Time	t _r				19		7
Turn-Off Delay Time	t _{d(OFF)}				50		ns
	.				.		1

5. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.

Fall Time

6. Switching characteristics are independent of operating junction temperatures.

 t_f

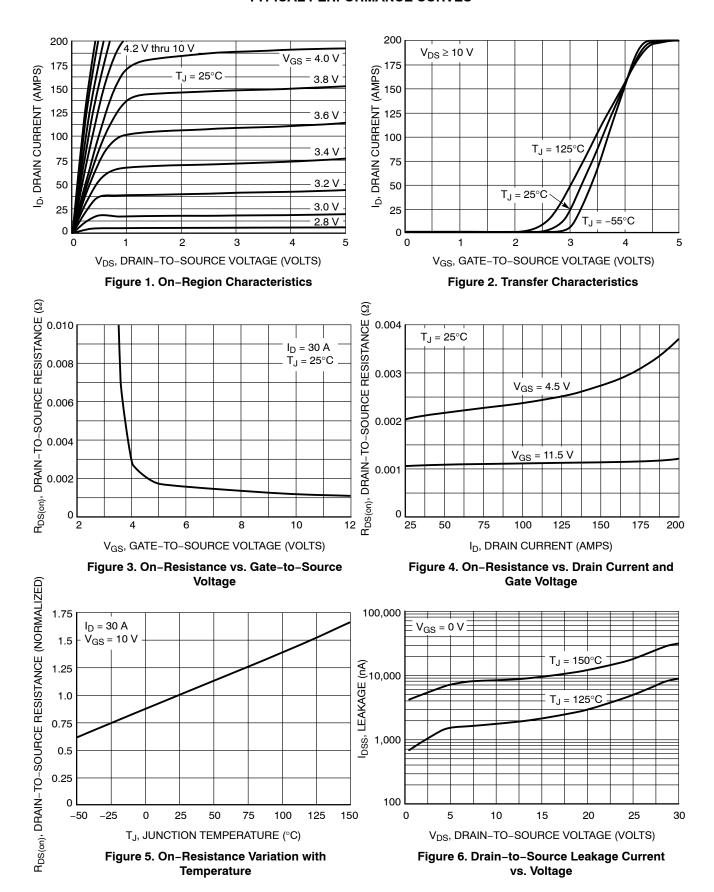
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ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

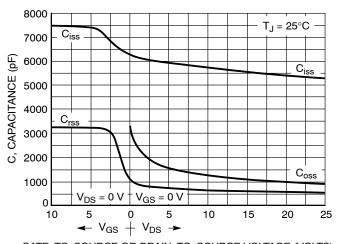
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
DRAIN-SOURCE DIODE CHARACTERISTICS								
Forward Diode Voltage	V_{SD}	V _{GS} = 0 V,	$T_J = 25^{\circ}C$	-	0.8	1.0	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	
		I _S = 30 A	T _J = 125°C	-	0.68	-	V	
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dIS/dt = 100 A/μs, I _S = 30 A		-	38	-		
Charge Time	t _a			-	19	-	ns	
Discharge Time	t _b			-	19	-		
Reverse Recovery Charge	Q_{RR}			-	36	-	nC	
PACKAGE PARASITIC VALUES								
Source Inductance	L _S	T _A = 25°C		-	0.50	-	nΗ	
Drain Inductance	L _D			-	0.005	-	nΗ	
Gate Inductance	L _G			-	1.84	-	nΗ	
Gate Resistance	R_{G}			-	1.0	-	Ω	

^{5.} Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES



TYPICAL PERFORMANCE CURVES



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

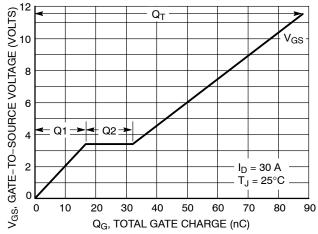


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge



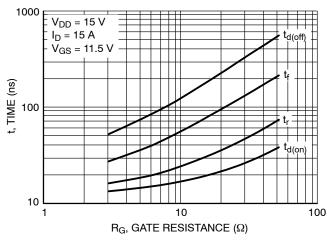


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

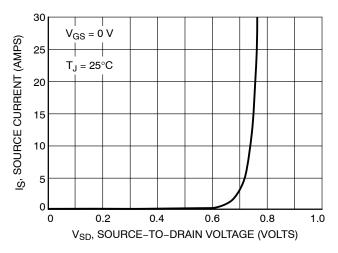


Figure 10. Diode Forward Voltage vs. Current

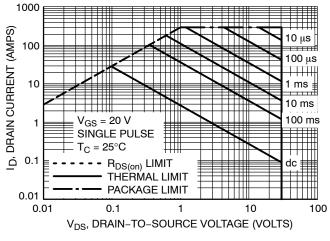


Figure 11. Maximum Rated Forward Biased Safe Operating Area

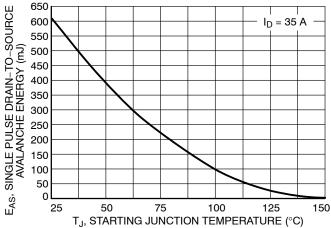


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL PERFORMANCE CURVES

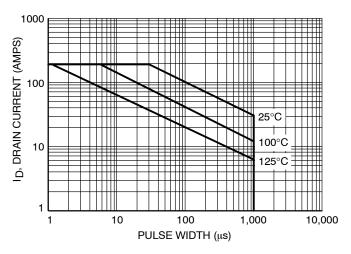


Figure 13. Avalanche Characteristics

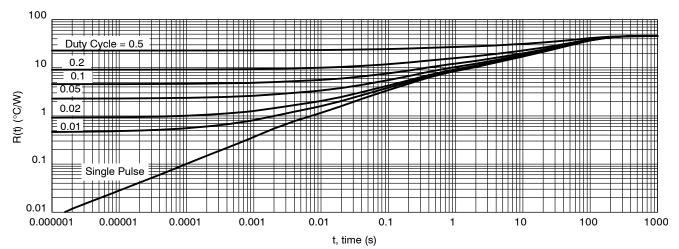
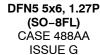
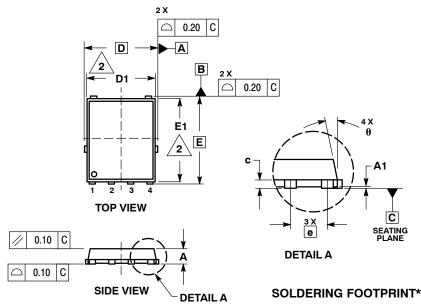


Figure 14. FET Thermal Response

PACKAGE DIMENSIONS



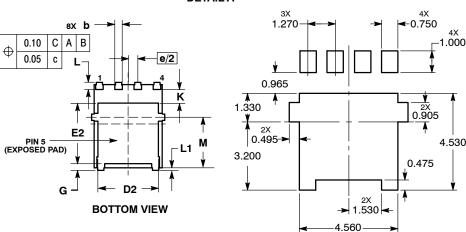


NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994
- CONTROLLING DIMENSION: MILLIMETER. DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE

	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	0.90	1.00	1.10	
A1	0.00		0.05	
b	0.33	0.41	0.51	
С	0.23	0.28	0.33	
D		5.15 BSC	;	
D1	4.50	4.90	5.10	
D2	3.50		4.22	
E	6.15 BSC			
E1	5.50	5.80	6.10	
E2	3.45		4.30	
е		1.27 BSC	;	
G	0.51	0.61	0.71	
K	1.20	1.35	1.50	
L	0.51	0.61	0.71	
L1	0.05	0.17	0.20	
М	3.00	3.40	3.80	
θ	0 °		12 °	

- STYLE 1: PIN 1. SOURCE
 - SOURCE
 SOURCE
 - GATE
 - 5. DRAIN



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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